



# 32Kx8 Static RAM

#### **Features**

- 4.5V-5.5V Operation
- Low active power (70 ns, LL version)
  - -275 mW (max.)
- Low standby power (70 ns, LL version)
  - -28 μW (max.)
- 55, 70 ns access time
- Easy memory expansion with CE and OE features
- · TTL-compatible inputs and outputs
- · Automatic power-down when deselected
- CMOS for optimum speed/power

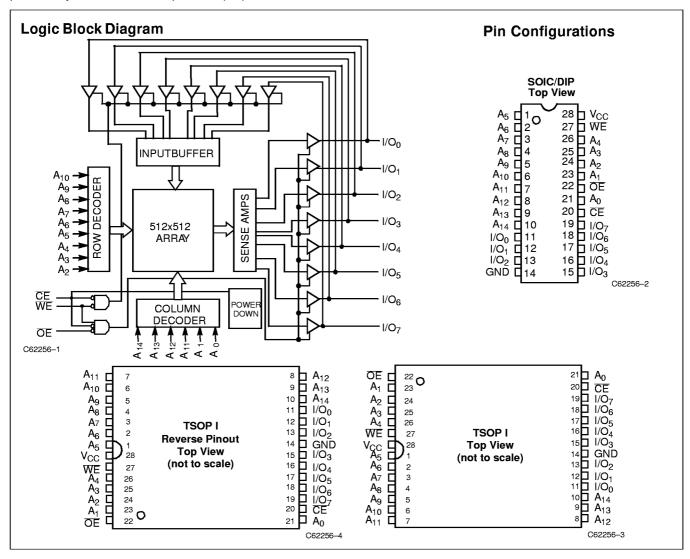
#### **Functional Description**

The CY62256 is a high-performance CMOS static RAM organized as 32,768 words by 8 bits. Easy memory expansion is provided by an active LOW chip enable (CE) and active LOW

output enable ( $\overline{OE}$ ) and three-state drivers. This device has an automatic power-down feature, reducing the power consumption by 99.9% when deselected. The CY62256 is in the standard 450-mil-wide (300-mil body width) SOIC, TSOP, and 600-mil PDIP packages.

An active LOW write enable signal ( $\overline{WE}$ ) controls the writing/reading operation of the memory. When  $\overline{CE}$  and  $\overline{WE}$  inputs are both LOW, data on the eight data input/output pins (I/O<sub>0</sub> through I/O<sub>7</sub>) is written into the memory location addressed by the address present on the address pins (A<sub>0</sub> through A<sub>14</sub>). Reading the device is accomplished by selecting the device and enabling the outputs,  $\overline{CE}$  and  $\overline{OE}$  active LOW, while  $\overline{WE}$  remains inactive or HIGH. Under these conditions, the contents of the location addressed by the information on address pins are present on the eight data input/output pins.

The input/output pins remain in a high-impedance state unless the chip is selected, outputs are enabled, and write enable (WE) is HIGH.





### **Maximum Ratings**

Output Current into Outputs (LOW)	20 mA
Static Discharge Voltage	>2001V
Latch-Up Current	>200 mA

### **Operating Range**

Range	Ambient Temperature	V <sub>cc</sub>
Commercial	0°C to +70°C	5V ± 10%
Industrial	–40°C to +85°C	5V ± 10%

## Electrical Characteristics Over the Operating Range

				(	Y62256	-55		CY62256-	-70	
Parameter	Description	Description Test Conditions		Min.	Typ <sup>[2]</sup>	Max.	Min.	Typ <sup>[2]</sup>	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -1.0 mA		2.4			2.4			V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 2.1	mΑ			0.4			0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.2		V <sub>CC</sub> +0.5V	2.2		V <sub>CC</sub> +0.5V	V
V <sub>IL</sub>	Input LOW Voltage			-0.5		8.0	-0.5		8.0	V
I <sub>IX</sub>	Input Load Current	$GND \le V_{I} \le V_{CC}$		-0.5		+0.5	-0.5		+0.5	μА
loz	Output Leakage Current	$GND \le V_O \le V_{CC}$ , Output Disabled		-0.5		+0.5	-0.5		+0.5	μА
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max.,			28	55		28	55	mA
		$I_{OUT} = 0 \text{ mA},$ $f = f_{MAX} = 1/t_{RC}$	L		25	50		25	50	mA
			LL		25	50		25	50	mA
I <sub>SB1</sub>	Automatic CE Power-Down Current— TTL Inputs				0.5	2		0.5	2	mA
		" " " " " " " " " " " " " " " " " " "	L		0.4	0.6		0.4	0.6	mA
			LL		0.3	0.5		0.3	0.5	mA
I <sub>SB2</sub>	Automatic CE	Max. V <sub>CC</sub> ,			1	5		1	5	mA
	Power-Down Current— CMOS Inputs	1 – 60	L		2	50		2	50	μΑ
			LL		0.1	5		0.1	5	μΑ
		Indust'l Temp Range	LL		0.1	10		0.1	10	μΑ

Shaded area contains preliminary information.

### Capacitance<sup>[3]</sup>

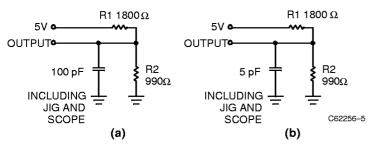
Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	6	pF
C <sub>OUT</sub>	Output Capacitance	$V_{CC} = 5.0V$	8	pF

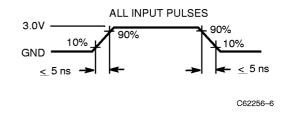
#### Note:

- 1.  $V_{IL}$  (min.) = -2.0V for pulse durations of less than 20 ns.
- 2. Typical specifications are the mean values measured over a large sample size across normal production process variations and are taken at nominal conditions (T<sub>A</sub> = 25°C, V<sub>CC</sub>). Parameters are guaranteed by design and characterization, and not 100% tested.
- 3. Tested initially and after any design or process changes that may affect these parameters.



## **AC Test Loads and Waveforms**



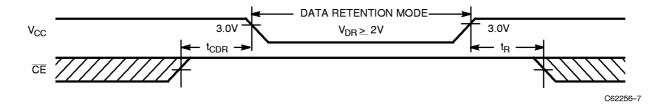


Equivalent to: THÉVENIN EQUIVALENT
639Ω
OUTPUT••••••••• 1.77V

### **Data Retention Characteristics**

Parameter	Description		Conditions <sup>[4]</sup>	Min.	<b>Typ</b> . <sup>[2]</sup>	Max.	Unit
$V_{\mathrm{DR}}$	V <sub>CC</sub> for Data Retention		$V_{CC} = 3.0V$	2.0			٧
I <sub>CCDR</sub>	Data Retention Current	L	$ \begin{array}{l} V_{CC} = 3.0V, \\ \hline CE \geq V_{CC} - 0.3V, \\ V_{IN} \geq V_{CC} - 0.3V \text{ or} \\ V_{IN} \leq 0.3V \end{array} $		2	50	μΑ
		LL	$V_{IN} \le 0.3V$		0.1	5	μΑ
		LL Indust'l			0.1	10	μΑ
t <sub>CDR</sub> <sup>[3]</sup>	Chip Deselect to Data Retention Time	•		0			ns
t <sub>R</sub> <sup>[3]</sup>	Operation Recovery Time	1		t <sub>RC</sub>			ns

### **Data Retention Waveform**



#### Note:

4. No input may exceed V<sub>CC</sub>+0.5V.



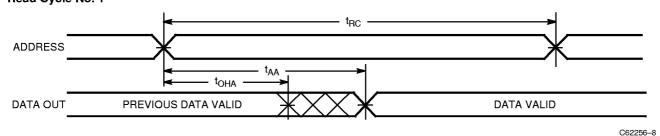
## Switching Characteristics Over the Operating Range<sup>[5]</sup>

		CY62	CY62256-55			
Parameter	Description	Min.	Max.	Min.	Max.	Unit
READ CYCLE	-	<u> </u>	4	×4		
t <sub>RC</sub>	Read Cycle Time	55		70		ns
t <sub>AA</sub>	Address to Data Valid		55		70	ns
t <sub>OHA</sub>	Data Hold from Address Change	5		5		ns
t <sub>ACE</sub>	CE LOW to Data Valid		55		70	ns
t <sub>DOE</sub>	OE LOW to Data Valid		25		35	ns
t <sub>LZOE</sub>	OE LOW to Low Z <sup>[6]</sup>	5		5		ns
t <sub>HZOE</sub>	OE HIGH to High Z <sup>[6, 7]</sup>		20		25	ns
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[6]</sup>	5		5		ns
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[6, 7]</sup>		20		25	ns
t <sub>PU</sub>	CE LOW to Power-Up	0		0		ns
t <sub>PD</sub>	CE HIGH to Power-Down		55		70	ns
WRITE CYCLE <sup>[8,</sup>	9]				•	•
t <sub>WC</sub>	Write Cycle Time	55		70		ns
t <sub>SCE</sub>	CE LOW to Write End	45		60		ns
t <sub>AW</sub>	Address Set-Up to Write End	45		60		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		ns
t <sub>PWE</sub>	WE Pulse Width	40		50		ns
t <sub>SD</sub>	Data Set-Up to Write End	25		30		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[6, 7]</sup>		20		25	ns
t <sub>LZWE</sub>	WE HIGH to Low Z <sup>[6]</sup>	5		5		ns

Shaded area contains preliminary information.

### **Switching Waveforms**

# Read Cycle No. 1<sup>[10,11]</sup>



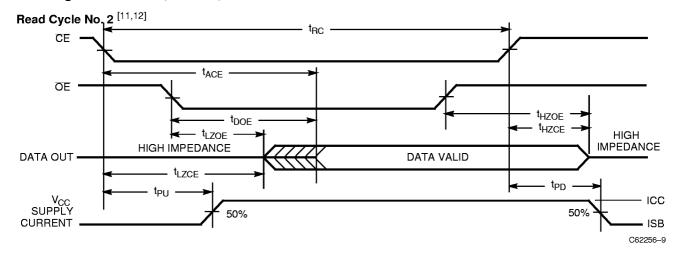
Notes:

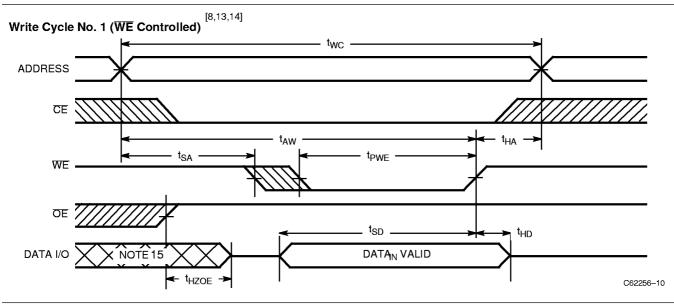
- Notes:
  Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified loL/loH and 100-pF load capacitance.
  At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.
  t<sub>HZCE</sub>, t<sub>HZCE</sub>, and t<sub>HZWE</sub> are specified with C<sub>L</sub> = 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
  The internal write time of the memory is defined by the overlap of CE LOW and WE LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
  The minimum write cycle time for write cycle #3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>
  Device is continuously selected. OE, CE = V<sub>IL</sub>.
  WE is HIGH for read cycle.

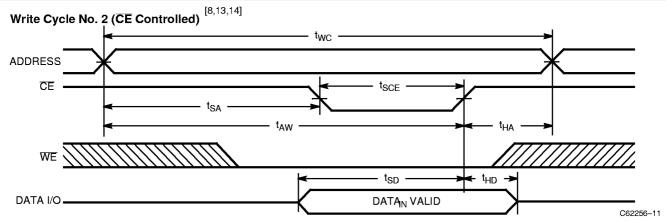
- 11. WE is HIGH for read cycle.



### Switching Waveforms (continued)







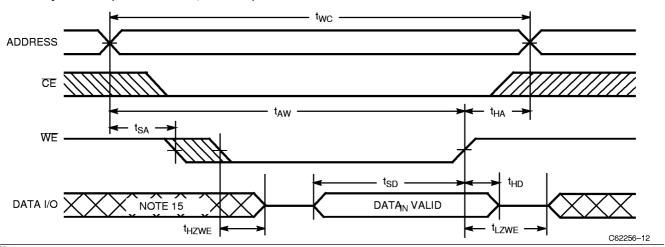
#### Notes:

- Address valid prior to or coincident with CE transition LOW.
   Data I/O is high impedance if OE = V<sub>IH</sub>.
   If CE goes HIGH simultaneously with WE HIGH, the output remains in a high-impedance state.



# Switching Waveforms (continued)

# Write Cycle No. 3 (WE Controlled, OE LOW)

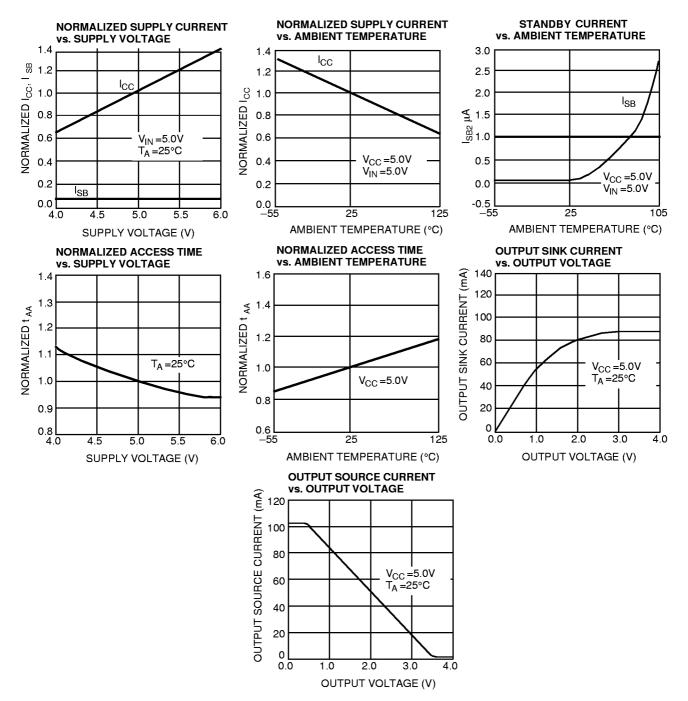


#### Note:

15. During this period, the I/Os are in output state and input signals should not be applied.

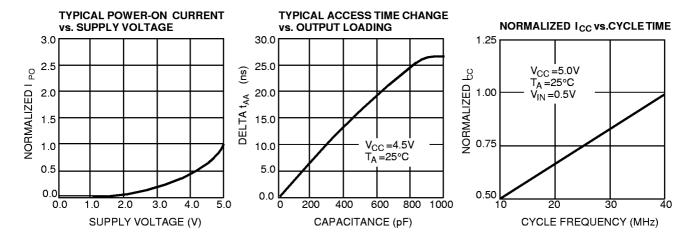


## Typical DC and AC Characteristics





# Typical DC and AC Characteristics (continued)



### **Truth Table**

CE	WE	OE	Inputs/Outputs	Mode	Power
Н	Х	Х	High Z	Deselect/Power-Down	Standby (I <sub>SB</sub> )
L	Н	L	Data Out	Read	Active (I <sub>CC</sub> )
L	L	Х	Data In	Write	Active (I <sub>CC</sub> )
L	Н	Н	High Z	Deselect, Output Disabled	Active (I <sub>CC</sub> )



# **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
55	CY62256-55SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	Commercial
	CY62256L-55SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256LL-55SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256-55ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256L-55ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256LL-55ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256-55ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256L-55ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256LL-55ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256-55PC	P15	28-Lead (600-Mil) Molded DIP	
70	CY62256-70SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	Commercial
	CY62256L-70SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256LL-70SNC	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256-70SNI	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	Industrial
	CY62256L-70SNI	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256LL-70SNI	S22	28-Lead 450-Mil (300-Mil Body Width) SOIC	
	CY62256-70ZC	Z28	28-Lead Thin Small Outline Package	Commercial
	CY62256L-70ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256LL-70ZC	Z28	28-Lead Thin Small Outline Package	
	CY62256-70ZI	Z28	28-Lead Thin Small Outline Package	Industrial
	CY62256L-70ZI	Z28	28-Lead Thin Small Outline Package	
	CY62256LL-70ZI	Z28	28-Lead Thin Small Outline Package	
	CY62256-70PC	P15	28-Lead (600-Mil) Molded DIP	Commercial
	CY62256L-70PC	P15	28-Lead (600-Mil) Molded DIP	
	CY62256LL-70PC	P15	28-Lead (600-Mil) Molded DIP	
	CY62256-70ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256L-70ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	
	CY62256LL-70ZRC	ZR28	28-Lead Reverse Thin Small Outline Package	

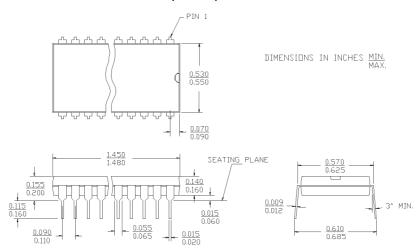
Shaded area contains preliminary information.

Document #: 38-00455-C

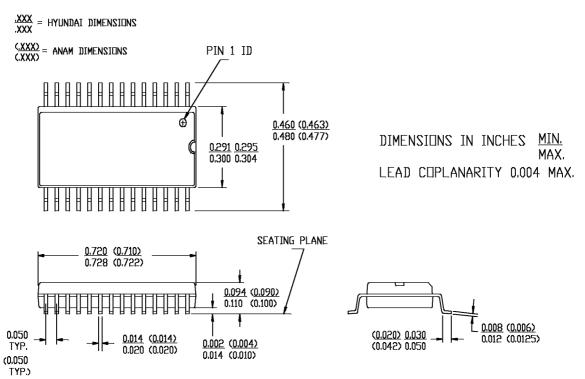


## **Package Diagrams**

### 28-Lead (600-Mil) Molded DIP P15



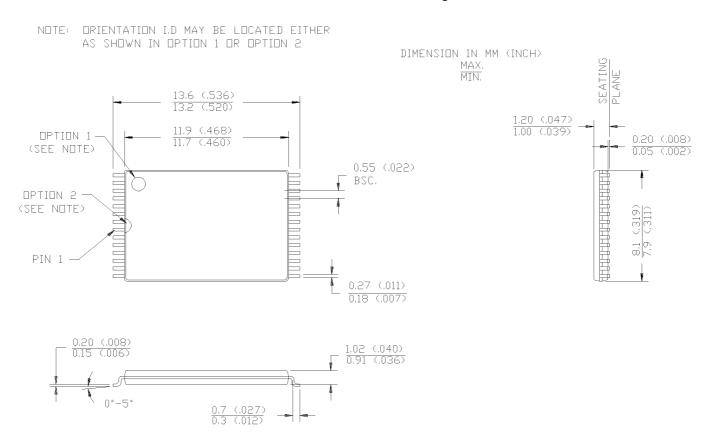
### 28-Lead 450-Mil (300-Mil Body Width) SOIC S22





# Package Diagrams (continued)

#### 28-Lead Thin Small Outline Package Z28





### Package Diagrams (continued)

#### 28-Lead Reverse Thin Small Outline Package ZR28

